

**Notice of References Cited**Application/Control No.  
10/088,114Applicant(s)/Patent Under  
Reexamination  
INOUE ET AL.Examiner  
John F. Belena, Ph.D.Art Unit  
3746

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,092,362	07-2000	Nagafuchi et al.	60/39.821
	B	US-5,660,045	08-1997	Ito et al.	60/737
	C	US-5,349,812	09-1994	Taniguchi et al.	60/39.23
	D	US-5,323,614	06-1994	Tsukahara et al.	60/737
	E	US-5,121,597	06-1992	Urushidani et al.	60/733
	F	US-5,069,029	12-1991	Kuroda et al.	60/737
	G	US-4,898,001	02-1990	Kuroda et al.	60/748
	H	US-4,677,822	07-1987	Iizuka et al.	60/747
	I	US-4,829,764	05-1989	Iizuka et al.	60/746
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP-408135969-A	05-1996	Japan	Yoshida et al.	--
	O	JP-362175524-A	08-1987	Japan	Iizuka et al.	--
	P	JP-361119920-A	06-1986	Japan	Iizuka et al.	--
	Q	JP-355046309-A	04-1980	Japan	Kusaba et al.	--
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.